

Description

The HBSC066N06NSATMA1 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS} = 60V I_D =80 A

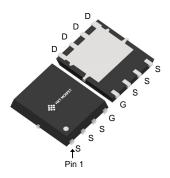
 $R_{DS(ON)} < 7m\Omega$ @ $V_{GS}=10V$

Application

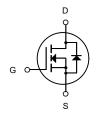
Battery protection

Load switch

Uninterruptible power supply



DFN5X6-8L (TDSON-8)



N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
HBSC066N06NSATMA1	DFN5X6-8L(TDSON-8)	HXY MOSFET	5000

Absolute Maximum Ratings (T_c=25[°]Cunless otherwise noted)

Symbol	Parameter	Rating	Units		
V _D s	Drain-Source Voltage	60	V		
Vgs	Gate-Source Voltage	ate-Source Voltage ±20			
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	Drain Current, V _{GS} @ 10V ¹ 80			
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	Drain Current, V _{GS} @ 10V ¹ 52			
Ім	Pulsed Drain Current ²	А			
EAS	Single Pulse Avalanche Energy³	Single Pulse Avalanche Energy ³ 169			
P _D @T _C =25°C	Total Power Dissipation ⁴	108	W		
Тѕтс	Storage Temperature Range	-55 to 150	°C		
TJ	Operating Junction Temperature Range	-55 to 150	°C		
Rejc	Thermal Resistance Junction-Case ¹	ance Junction-Case ¹ 1.4			

Electrical Characteristics (T_J=25°C unless other wises pecified)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
Off Charac	cteristic					
V _{(BR)D} s	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250µA	60	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =60V, V _{GS} =0V,	-	-	1.0	μA
I _{GSS}	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} =±20V	-	-	±100	nA
On Claract	teristics					
$V_{GS(th)}$	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =2 50μA	2	3	4	V
R _{DS(on)}	Static Drain-Source on-Resistance	V _{GS} =10V, I _D = 30A -			7	mΩ
Dynamic (Characteristics					
C _{iss}	Input Capacitance	V _{DS} =30V,	-	4136	-	pF
Coss	Output Capacitance	V _{GS} =0V,	-	286	-	pF
C _{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	257	-	pF
Qa	Total Gate Charge	V -20V	-	90	-	nC
Q _{gs}	Gate-Source Charge	V _{DS} =30V,	-	9	-	nC
Q_{qd}	Gate-Drain("Miller") Charge	I _D =30A, V _{GS} =10V	-	18	-	nC
J	Characteristics					
t _{d(on)}	Turn-on Delay Time		-	9	-	ns
t _r	Turn-on Rise Time	V _{DS} =30V, I _D =30A,	-	7	-	ns
t _{d(off)}	Turn-off Delay Time	R _G =1.8Ω, V _{GS} =10V	-	40	-	ns
t _f	Turn-off Fall Time		-	15	-	ns
DrainSour	ce Diode Characteristics and Maximu	ım Ratings				
Is	Maximum Continuous Drain to Source Diode Forward Current		-	-	80	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			-	320	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} =0VI _S =30A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time		-	33	-	ns
Qrr	Body Diode Reverse Recovery Charge	I _F =30A, dI/dt=100A/μs	-	46	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

- 2. EAS condition : T_J=25 $^{\circ}$ C, V_{DD}=30V, V_G=10V, L=0.5mH, Rg=25 Ω , I_{AS}=26A
- 3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%



Typical Performance Characteristics

Figure1: Output Characteristics

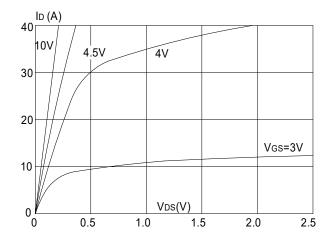


Figure 3:On-resistance vs. Drain Current

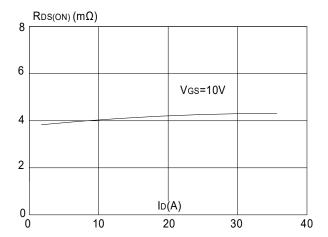


Figure 5: Gate Charge Characteristics

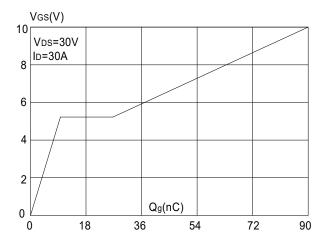


Figure 2: Typical Transfer Characteristics

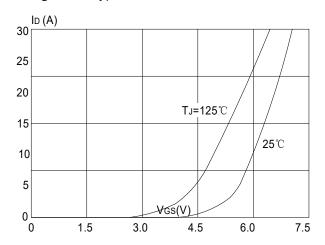


Figure 4: Body Diode Characteristics

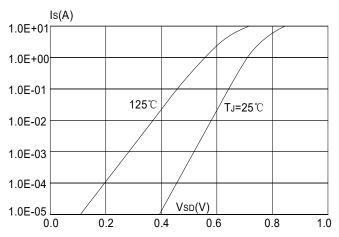
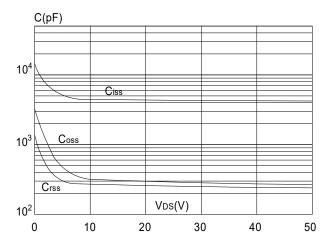


Figure 6: Capacitance Characteristics



N-Channel Enhancement Mode MOSFET

Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

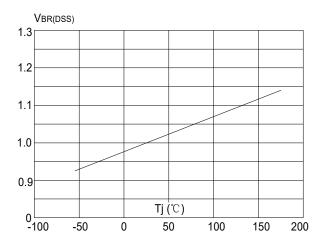


Figure 9: Maximum Safe Operating Area

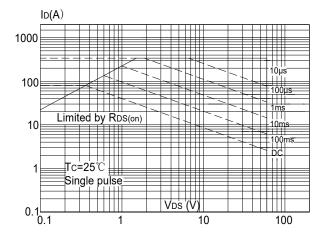


Figure.11: Maximum Effective
Transient Thermal Impedance, Junction-to-Case
ZthJ-c(°C/W)

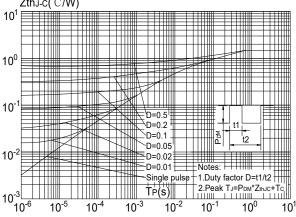


Figure 8: Normalized on Resistance vs. Junction Temperature

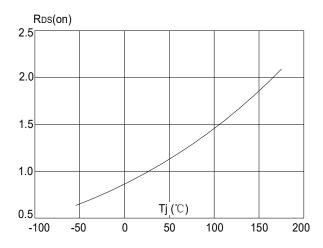
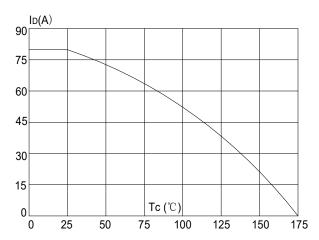
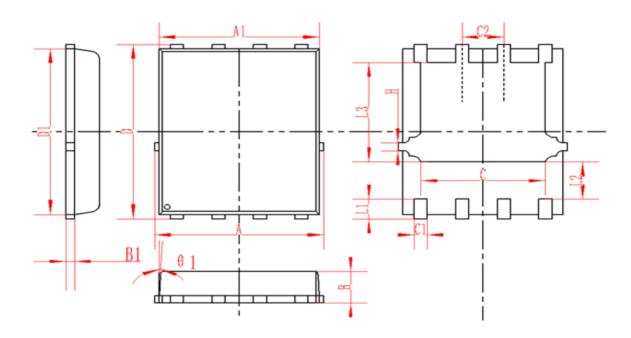


Figure 10: Maximum Continuous Drain Current vs. Case Temperature



N-Channel Enhancement Mode MOSFET

DFN5X6-8L(TDSON-8) Package Information



SYMBOL	MM		INCH			
STIVIDOL	MIN	NOM	MAX	MIN	NOM	MAX
А	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
В	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF		0.010REF			
С	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2		1.27TYP			0.5TYP	
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
Н	0.24	0.25	0.26	0.009	0.010	0.010

HBSC066N06NSATMA1

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